



# DIM1000ECM33-TS000

# **IGBT Chopper Module**

DS6091-3 September 2014 (LN31962)

Replaces DS6091-2

## **FEATURES**

- 10µs Short Circuit Withstand
- High Thermal Cycling Capability
- High Current Density Enhanced DMOS SPT
- Isolated AISiC Base with AIN Substrates

#### **APPLICATIONS**

- High Reliability Inverters
- Motor Controllers
- Traction Drives
- Choppers

The Powerline range of high power modules includes half bridge, chopper, dual, single and bi-directional switch configurations covering voltages from 1200V to 6500V and currents up to 2400A.

The DIM1000ECM33-TS000 is a 3300V, soft punch through n-channel enhancement mode, insulated gate bipolar transistor (IGBT) chopper module. The IGBT has a wide reverse bias safe operating area (RBSOA) plus 10µs short circuit withstand. This device is optimised for traction drives and other applications requiring high thermal cycling capability.

The module incorporates an electrically isolated base plate and low inductance construction enabling circuit designers to optimise circuit layouts and utilise grounded heat sinks for safety.

## **ORDERING INFORMATION**

Order As:

## DIM1000ECM33-TS000

Note: When ordering, please use the complete part number

#### **KEY PARAMETERS**

$V_{CES}$		3300V
$V_{CE(sat)}$	* (typ)	2.2V
I <sub>C</sub>	(max)	1000A
I <sub>C(PK)</sub>	(max)	2000A

<sup>\*</sup> Measured at the auxiliary terminals

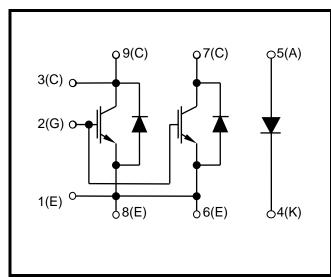


Fig. 1 Circuit configuration



Fig. 2 Package



## **ABSOLUTE MAXIMUM RATINGS**

Stresses above those listed under 'Absolute Maximum Ratings' may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed. Exposure to Absolute Maximum Ratings may affect device reliability.

T<sub>case</sub> = 25°C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
V <sub>CES</sub>	Collector-emitter voltage	V <sub>GE</sub> = 0V	3300	V
$V_{GES}$	Gate-emitter voltage		±20	V
I <sub>C</sub>	Continuous collector current	$T_{case} = 110$ °C	1000	Α
$I_{C(PK)}$	Peak collector current	1ms, T <sub>case</sub> = 140°C	2000	Α
P <sub>max</sub>	Max. transistor power dissipation	$T_{case} = 25^{\circ}C, T_{j} = 150^{\circ}C$	10.4	kW
l <sup>2</sup> t	Diode I <sup>2</sup> t value (IGBT arm)	V 0 4 40 W T 40500		kA <sup>2</sup> s
1 1 1	Diode I <sup>2</sup> t value (Diode arm)	$V_R = 0$ , $t_p = 10$ ms, $T_j = 125$ °C	320	kA <sup>2</sup> s
V <sub>isol</sub>	Isolation voltage – per module	Commoned terminals to base plate. AC RMS, 1 min, 50Hz	6000	V
$Q_PD$	Partial discharge – per module	IEC1287, V <sub>1</sub> = 3500V, V <sub>2</sub> = 2600V, 50Hz RMS	10	рС

## THERMAL AND MECHANICAL RATINGS

Internal insulation material:

Baseplate material:

Creepage distance:

Clearance:

CTI (Comparative Tracking Index):

AIN

AISiC

31mm

20mm

>600

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
R <sub>th(j-c)</sub>	Thermal resistance – transistor	Continuous dissipation – junction to case	-	-	12	°C/kW
R <sub>th(j-c)</sub>	Thermal resistance – diode (IGBT arm)	Continuous dissipation – junction to case	ı	-	24	°C/kW
R <sub>th(j-c)</sub>	Thermal resistance – diode (Diode arm)	Continuous dissipation – junction to case	-	-	24	°C/kW
R <sub>th(c-h)</sub>	Thermal resistance – case to heatsink (per module)	Mounting torque 5Nm (with mounting grease)	1	-	8	°C/kW
_	Junction temperature	Transistor	-	-	150	°C
$T_{j}$		Diode	-	-	150	°C
T <sub>stg</sub>	Storage temperature range	-	-40	-	125	°C
		Mounting – M6	-	-	5	Nm
	Screw torque	Electrical connections – M4	-	-	2	Nm
		Electrical connections – M8	-	-	10	Nm



## **ELECTRICAL CHARACTERISTICS**

 $T_{case}$  = 25°C unless stated otherwise.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
I <sub>CES</sub>		$V_{GE} = 0V$ , $V_{CE} = V_{CES}$			4	mA
	Collector cut-off current	$V_{GE} = 0V$ , $V_{CE} = V_{CES}$ , $T_{case} = 125$ °C			60	mA
		$V_{GE} = 0V$ , $V_{CE} = V_{CES}$ , $T_{case} = 150$ °C			100	mA
I <sub>GES</sub>	Gate leakage current	$V_{GE} = \pm 20V, V_{CE} = 0V$			1	μA
V <sub>GE(TH)</sub>	Gate threshold voltage	$I_C = 80$ mA, $V_{GE} = V_{CE}$		5.7		V
		V <sub>GE</sub> = 15V, I <sub>C</sub> = 1000A		2.2		V
V <sub>CE(sat)</sub> †	Collector-emitter saturation voltage	V <sub>GE</sub> = 15V, I <sub>C</sub> = 1000A, T <sub>j</sub> = 125°C		2.8		V
		V <sub>GE</sub> = 15V, I <sub>C</sub> = 1000A, T <sub>j</sub> = 150°C		3.0		V
I <sub>F</sub>	Diode forward current	DC		1000		Α
I <sub>FM</sub>	Diode maximum forward current	t <sub>p</sub> = 1ms		2000		Α
	Diode forward voltage (IGBT & Diode arm)	I <sub>F</sub> = 1000A		2.4		V
$V_F^{\dagger}$		I <sub>F</sub> = 1000A, T <sub>j</sub> = 125°C		2.5		V
	,	I <sub>F</sub> = 1000A, T <sub>j</sub> = 150°C		2.4		V
C <sub>ies</sub>	Input capacitance	V <sub>CE</sub> = 25V, V <sub>GE</sub> = 0V, f = 1MHz		170		nF
$Q_g$	Gate charge	±15V Including external C <sub>ge</sub>		17		μC
C <sub>res</sub>	Reverse transfer capacitance	V <sub>CE</sub> = 25V, V <sub>GE</sub> = 0V, f = 1MHz		4		nF
ı	Module inductance	IGBT		15		nH
$L_M$		Diode		25		
0		IGBT		135		
R <sub>INT</sub>	Internal resistance	Diode		270		μΩ
SC <sub>Data</sub>	Short circuit current, I <sub>SC</sub>	$T_j = 150^{\circ}C$ , $V_{CC} = 2500V$ $t_p \le 10\mu s$ , $V_{GE} \le 15V$ $V_{CE (max)} = V_{CES} - L^* x dI/dt$ IEC 60747-9		3700		А

Note: † Measured at the auxiliary terminals † L is the circuit inductance +  $L_{\text{M}}$ 



## **ELECTRICAL CHARACTERISTICS**

T<sub>case</sub> = 25°C unless stated otherwise

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
t <sub>d(off)</sub>	Turn-off delay time	I <sub>C</sub> = 1000A		2700		ns
t <sub>f</sub>	Fall time	$V_{GE} = \pm 15V$		520		ns
E <sub>OFF</sub>	Turn-off energy loss	$V_{CE} = 1800V$		1950		mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)} = 2.7\Omega$ $R_{G(OFF)} = 2.2\Omega$		1000		ns
t <sub>r</sub>	Rise time	$C_{qe} = 220nF$		400		ns
E <sub>ON</sub>	Turn-on energy loss	L <sub>S</sub> ~ 100nH		1300		mJ
$Q_{rr}$	Diode reverse recovery charge	I <sub>F</sub> = 1000A		570		μC
I <sub>rr</sub>	Diode reverse recovery current	$V_{CE} = 1800V$		615		Α
E <sub>rec</sub>	Diode reverse recovery energy	$dI_F/dt = 2700A/\mu s$		670		mJ

## T<sub>case</sub> = 125°C unless stated otherwise

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
t <sub>d(off)</sub>	Turn-off delay time	I <sub>C</sub> = 1000A		2750		ns
$t_f$	Fall time	$V_{GE} = \pm 15V$		570		ns
E <sub>OFF</sub>	Turn-off energy loss	$V_{CE} = 1800V$		2200		mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)} = 2.7\Omega$ $R_{G(OFF)} = 2.2\Omega$		1020		ns
t <sub>r</sub>	Rise time	$C_{qe} = 220nF$		420		ns
E <sub>ON</sub>	Turn-on energy loss	L <sub>S</sub> ~ 100nH		1700		mJ
$Q_{rr}$	Diode reverse recovery charge	$I_F = 1000A$		935		μC
I <sub>rr</sub>	Diode reverse recovery current	$V_{CE} = 1800V$		775		Α
E <sub>rec</sub>	Diode reverse recovery energy	$dI_F/dt = 2700A/\mu s$		1150		mJ

## T<sub>case</sub> = 150°C unless stated otherwise

Symbol	Parameter	Test Conditions	Min	Тур.	Max	Units
t <sub>d(off)</sub>	Turn-off delay time	I <sub>C</sub> = 1000A		2800		ns
t <sub>f</sub>	Fall time	$V_{GE} = \pm 15V$		550		ns
E <sub>OFF</sub>	Turn-off energy loss	$V_{CE} = 1800V$		2300		mJ
t <sub>d(on)</sub>	Turn-on delay time	$R_{G(ON)} = 2.7\Omega$ $R_{G(OFF)} = 2.2\Omega$		1030		ns
t <sub>r</sub>	Rise time	$C_{qe} = 220 nF$		430		ns
E <sub>ON</sub>	Turn-on energy loss	L <sub>s</sub> ~ 100nH		1850		mJ
Q <sub>rr</sub>	Diode reverse recovery charge	I <sub>F</sub> = 1000A		1070		μC
I <sub>rr</sub>	Diode reverse recovery current	V <sub>CE</sub> = 1800V		800		Α
E <sub>rec</sub>	Diode reverse recovery energy	dI <sub>F</sub> /dt = 2700A/μs		1300		mJ



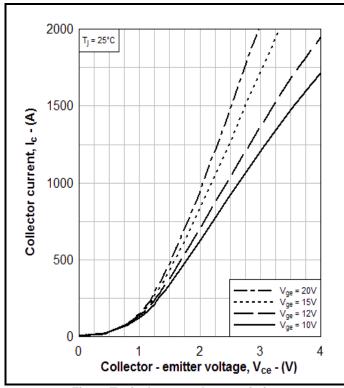


Fig. 3 Typical output characteristics

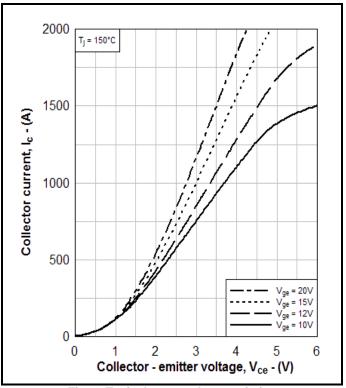


Fig. 4 Typical output characteristics

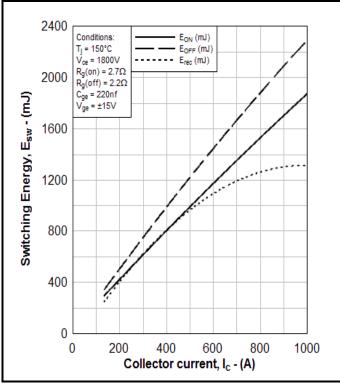


Fig. 5 Typical switching energy vs collector current

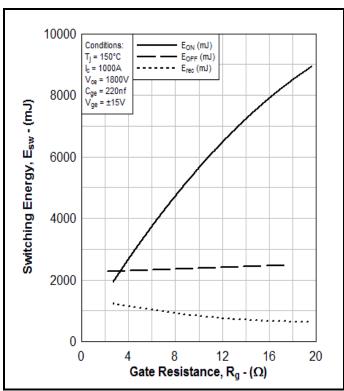


Fig. 6 Typical switching energy vs gate resistance



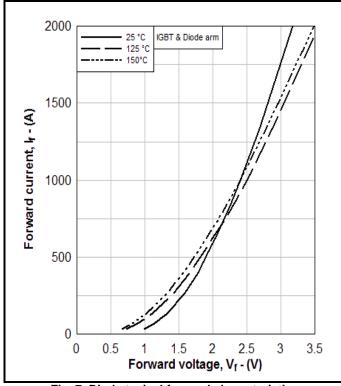


Fig. 7 Diode typical forward characteristics

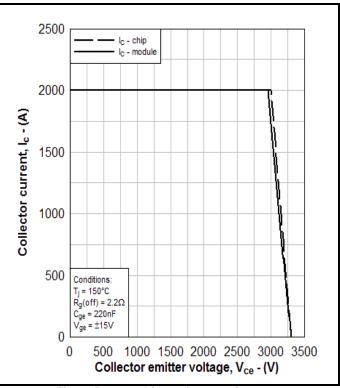


Fig. 8 Reverse bias safe operating area

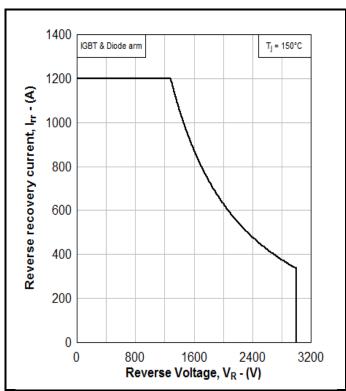


Fig. 9 Diode reverse bias safe operating area

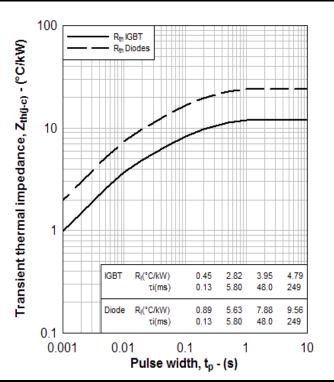


Fig. 10 Transient thermal impedance



## **PACKAGE DETAILS**

For further package information, please visit our website or contact Customer Services. All dimensions in mm, unless stated otherwise.

## DO NOT SCALE.

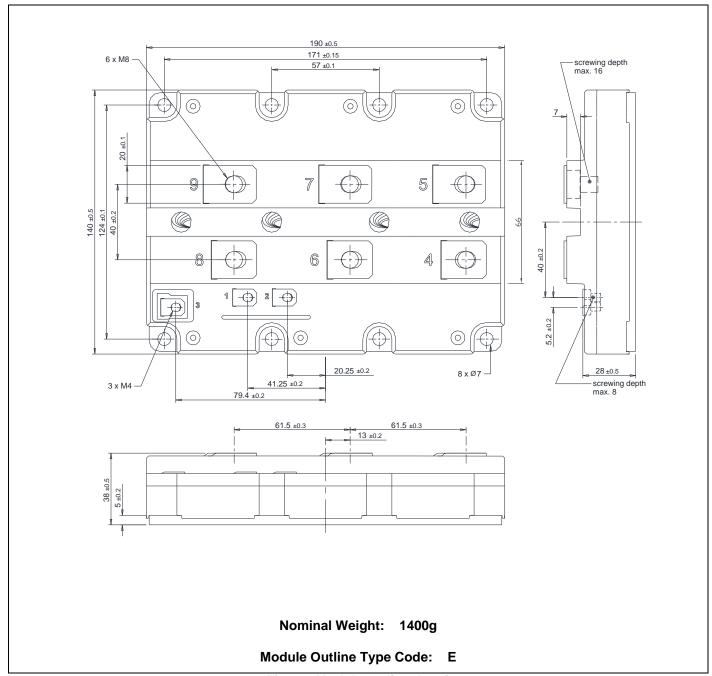


Fig. 11 Module outline drawing



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